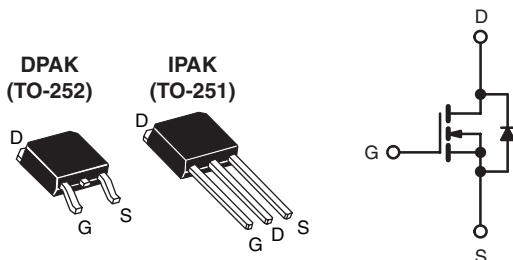


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	500	
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	3.0
Q_g (Max.) (nC)	17	
Q_{gs} (nC)	4.3	
Q_{gd} (nC)	8.5	
Configuration	Single	



N-Channel MOSFET

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{oss} Specified
- Lead (Pb)-free Available



APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching

ORDERING INFORMATION

Package	DPAK (TO-252)	DPAK (TO-252)	DPAK (TO-252)	IPAK (TO-251)
Lead (Pb)-free	IRFR420APbF	IRFR420ATRPbF ^a	IRFR420ATRLPbF	IRFU420APbF
	SiHFR420A-E3	SiHFR420AT-E3 ^a	SiHFR420ATL-E3	SiHFU420A-E3
SnPb	IRFR420A	-	-	IRFU420A
	SiHFR420A	-	-	SiHFU420A

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	500	V
Gate-Source Voltage	V_{GS}	± 30	
Continuous Drain Current	I_D	3.3	A
		2.1	
Pulsed Drain Current ^a	I_{DM}	10	
Linear Derating Factor		0.67	W/°C
Single Pulse Avalanche Energy ^b	E_{AS}	140	mJ
Repetitive Avalanche Current ^a	I_{AR}	2.5	A
Repetitive Avalanche Energy ^a	E_{AR}	5.0	mJ
Maximum Power Dissipation	P_D	83	W
Peak Diode Recovery dV/dt ^c	dV/dt	3.4	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting $T_J = 25$ °C, $L = 45$ mH, $R_G = 25$ Ω, $I_{AS} = 2.5$ A (see fig. 12).
- $I_{SD} \leq 2.5$ A, $dI/dt \leq 270$ A/μs, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

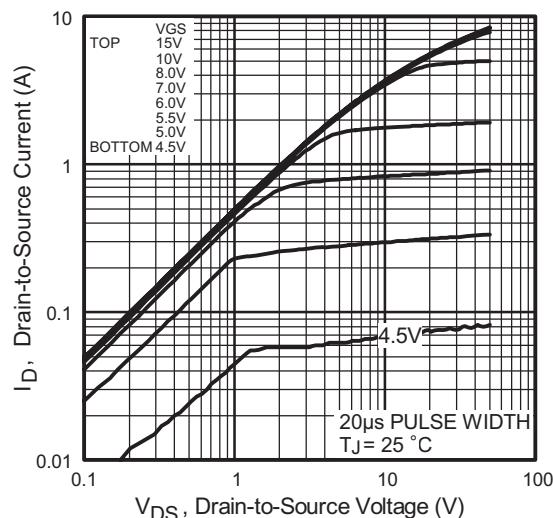
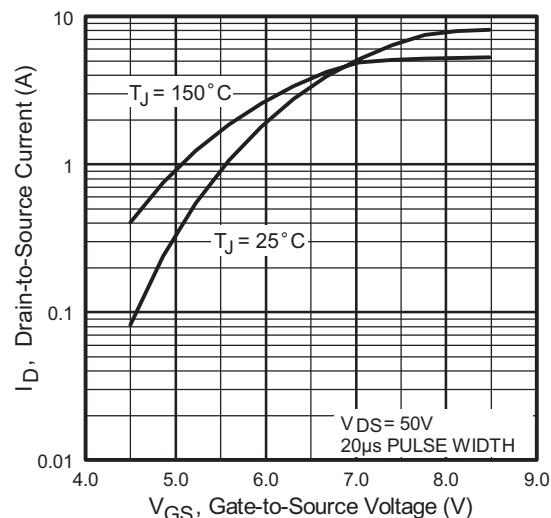
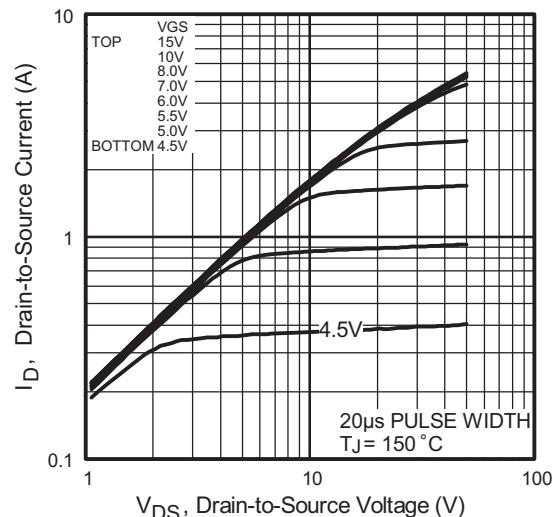
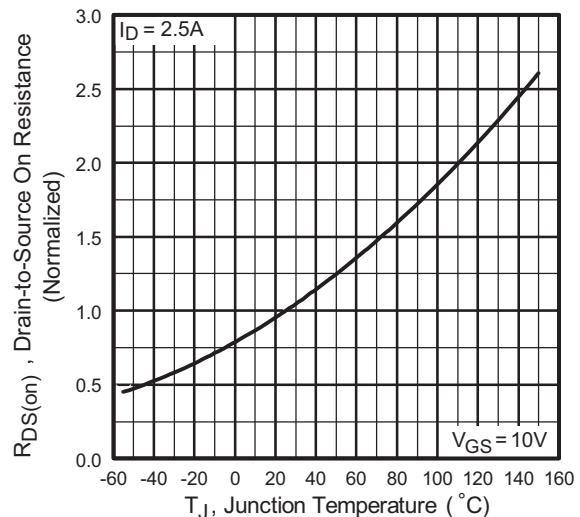
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.5	

SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	500	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	0.60	-	$^{\circ}\text{C}/\text{V}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.5	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 400 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125 \text{ }^{\circ}\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 1.5 \text{ A}^b$	-	-	3.0	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 1.5 \text{ A}$		1.4	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	340	-	pF	
Output Capacitance	C_{oss}			-	53	-		
Reverse Transfer Capacitance	C_{rss}			-	2.7	-		
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	490	-	pF	
			$V_{DS} = 400 \text{ V}$, $f = 1.0 \text{ MHz}$	-	15	-		
Effective Output Capacitance	$C_{oss eff.}$		$V_{DS} = 0 \text{ V}$ to 400 V^c	-	28	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 2.5 \text{ A}$, $V_{DS} = 400 \text{ V}$, see fig. 6 and 13 ^b	-	-	17	nC	
Gate-Source Charge	Q_{gs}			-	-	4.3		
Gate-Drain Charge	Q_{gd}			-	-	8.5		
Turn-On Delay Time	$t_{d(on)}$			-	8.1	-		
Rise Time	t_r	$V_{DD} = 250 \text{ V}$, $I_D = 2.5 \text{ A}$, $R_G = 21 \Omega$, $R_D = 97 \Omega$, see fig. 10 ^b		-	12	-	ns	
Turn-Off Delay Time	$t_{d(off)}$			-	16	-		
Fall Time	t_f			-	13	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.3	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	10		
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 2.5 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.6	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_F = 2.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	330	500	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	760	1140	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.
- c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFR420A, IRFU420A, SiHFR420A, SiHFU420A

Vishay Siliconix

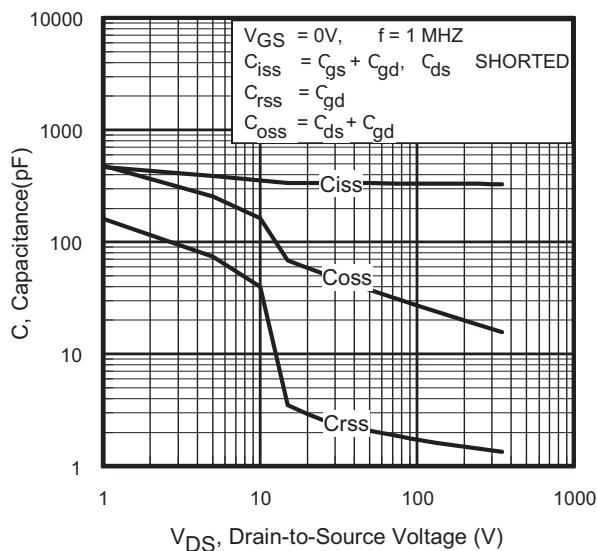


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

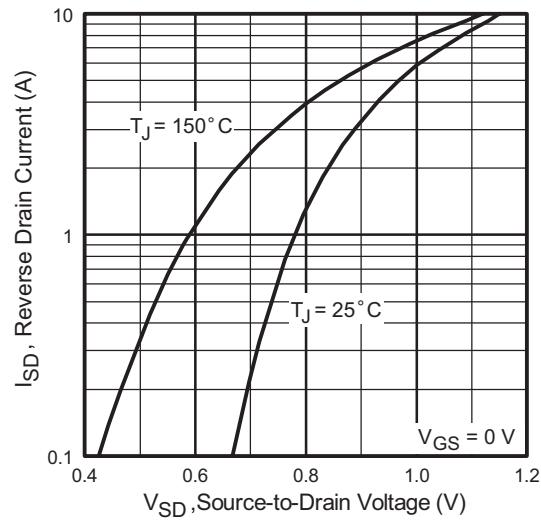


Fig. 7 - Typical Source-Drain Diode Forward Voltage

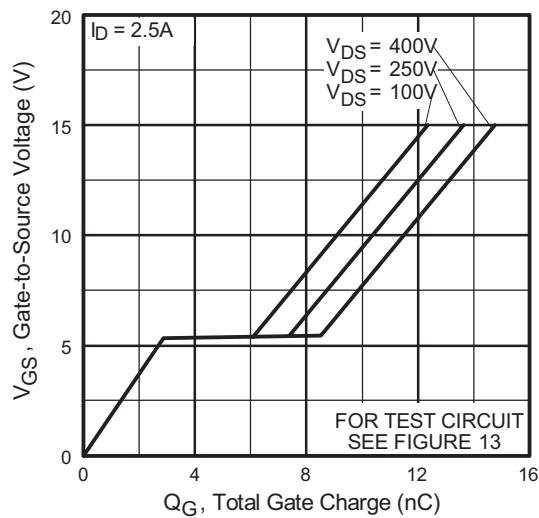


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

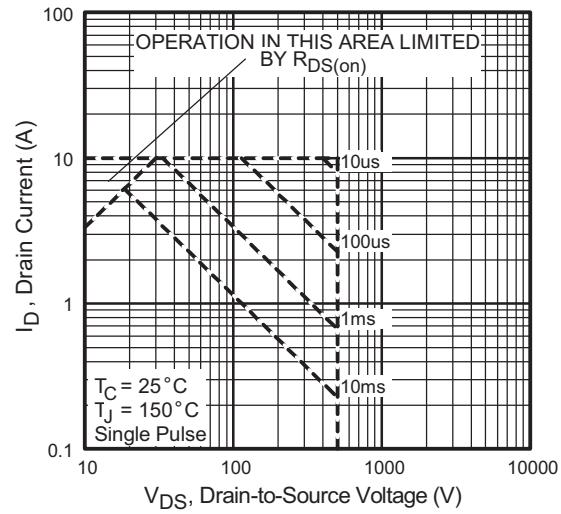
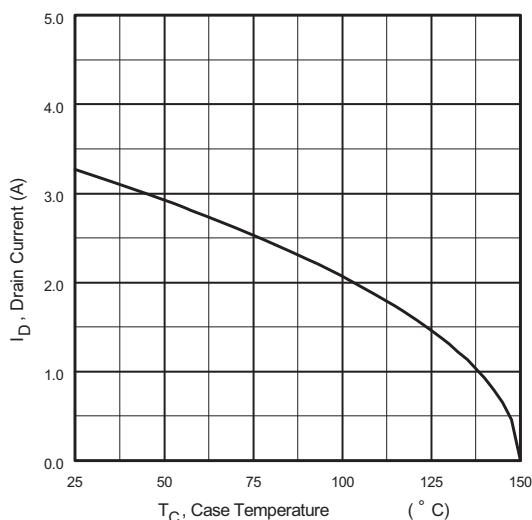
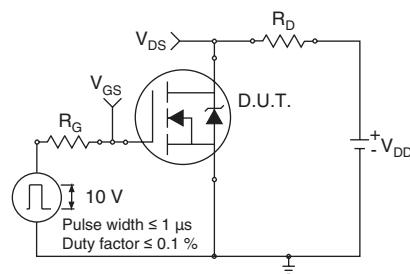
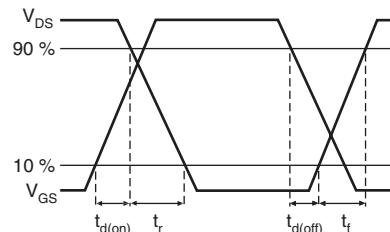
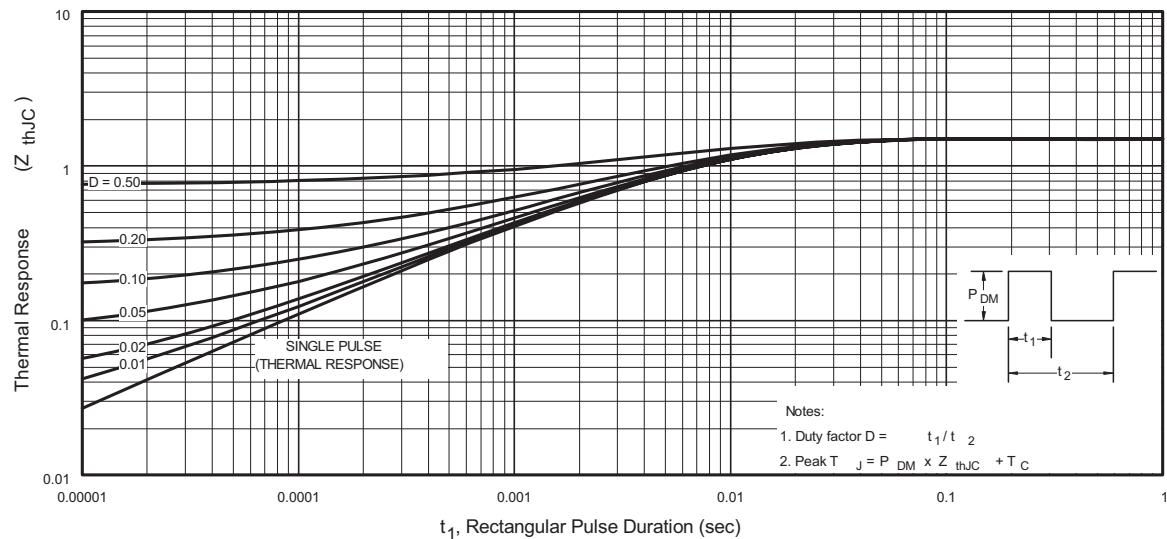
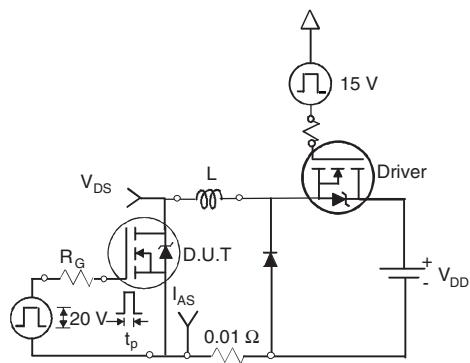
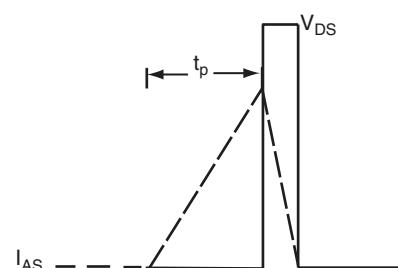


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

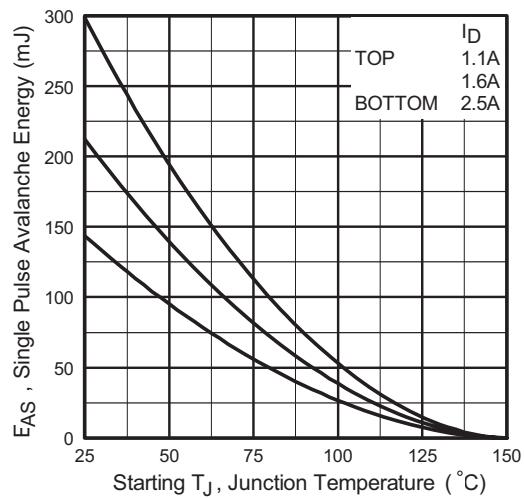


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

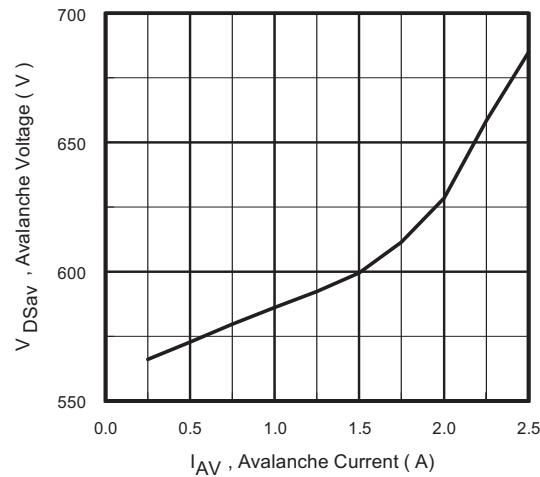


Fig. 12d - Maximum Avalanche Energy vs. Drain Current

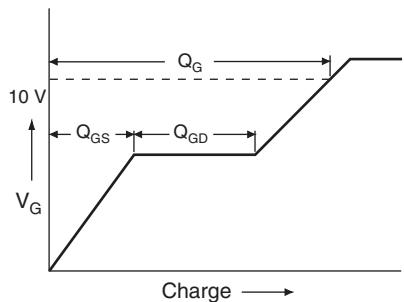


Fig. 13a - Basic Gate Charge Waveform

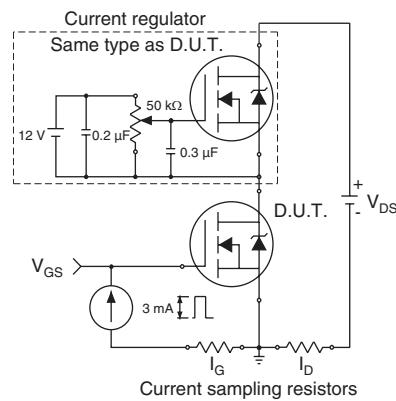
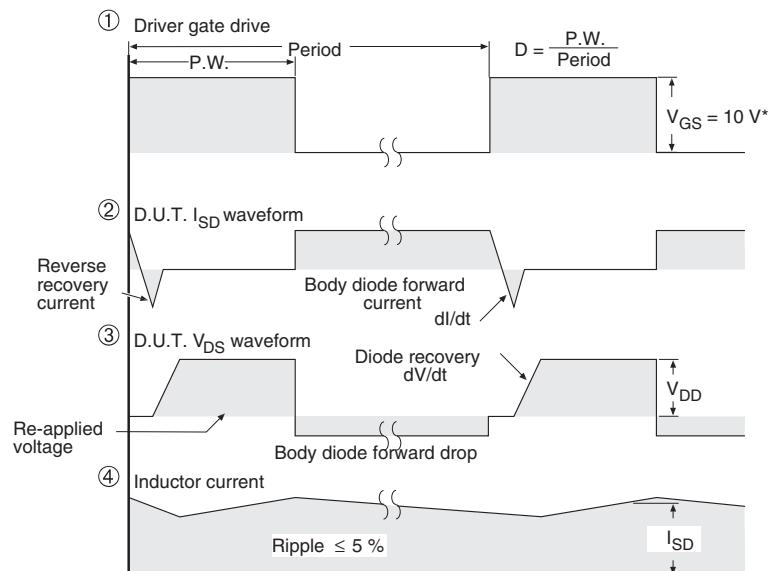
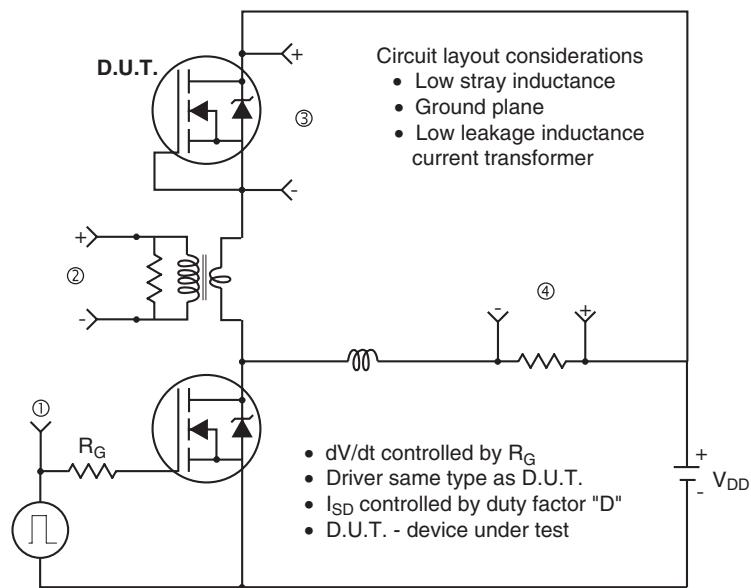


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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